

<b>Notice of References Cited</b>	Application/Control No. 10/575,738		Applicant(s)/Patent Under Reexamination ARKNAES-PEDERSEN ET AL.	
	Examiner Khanh V. Nguyen		Art Unit 2817	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,974,089	10-1999	Tripathi et al.	330/10
*	B	US-6,140,875	10-2000	Van Den Homberg et al.	330/251
	C	US-			
	D	US-			
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	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	JP2004-201187	07-2004	JAPAN	Akamine et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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